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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	1452
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	24000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx16a-1tq144

Power-Up/Down and Hot Swapping

SX-A I/Os are configured to be hot-swappable, with the exception of 3.3 V PCI. During power-up/down (or partial up/down), all I/Os are tristated. V_{CCA} and V_{CCI} do not have to be stable during power-up/down, and can be powered up/down in any order. When the SX-A device is plugged into an electrically active system, the device will not degrade the reliability of or cause damage to the host system. The device's output pins are driven to a high impedance state until normal chip operating conditions

are reached. Table 1-4 summarizes the V_{CCA} voltage at which the I/Os behave according to the user's design for an SX-A device at room temperature for various ramp-up rates. The data reported assumes a linear ramp-up profile to 2.5 V. For more information on power-up and hot-swapping, refer to the application note, *Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications*.

Table 1-2 • I/O Features

Function	Description
Input Buffer Threshold Selections	5 V: PCI, TTL 3.3 V: PCI, LVTTTL 2.5 V: LVCMOS2 (commercial only)
Flexible Output Driver	5 V: PCI, TTL 3.3 V: PCI, LVTTTL 2.5 V: LVCMOS2 (commercial only)
Output Buffer	"Hot-Swap" Capability (3.3 V PCI is not hot swappable) - I/O on an unpowered device does not sink current - Can be used for "cold-sparing" Selectable on an individual I/O basis Individually selectable slew rate; high slew or low slew (The default is high slew rate). The slew is only affected on the falling edge of an output. Rising edges of outputs are not affected.
Power-Up	Individually selectable pull-ups and pull-downs during power-up (default is to power-up in tristate) Enables deterministic power-up of device V_{CCA} and V_{CCI} can be powered in any order

Table 1-3 • I/O Characteristics for All I/O Configurations

	Hot Swappable	Slew Rate Control	Power-Up Resistor
TTL, LVTTTL, LVCMOS2	Yes	Yes. Only affects falling edges of outputs	Pull-up or pull-down
3.3 V PCI	No	No. High slew rate only	Pull-up or pull-down
5 V PCI	Yes	No. High slew rate only	Pull-up or pull-down

Table 1-4 • Power-Up Time at which I/Os Become Active

Supply Ramp Rate	0.25 V/ μ s	0.025 V/ μ s	5 V/ms	2.5 V/ms	0.5 V/ms	0.25 V/ms	0.1 V/ms	0.025 V/ms
Units	μ s	μ s	ms	ms	ms	ms	ms	ms
A54SX08A	10	96	0.34	0.65	2.7	5.4	12.9	50.8
A54SX16A	10	100	0.36	0.62	2.5	4.7	11.0	41.6
A54SX32A	10	100	0.46	0.74	2.8	5.2	12.1	47.2
A54SX72A	10	100	0.41	0.67	2.6	5.0	12.1	47.2

Pin Description

CLKA/B, I/O **Clock A and B**

These pins are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. The clock input is buffered prior to clocking the R-cells. When not used, this pin must be tied Low or High (NOT left floating) on the board to avoid unwanted power consumption.

For A54SX72A, these pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only. When not used, these pins must be tied Low or High (NOT left floating).

QCLKA/B/C/D, I/O **Quadrant Clock A, B, C, and D**

These four pins are the quadrant clock inputs and are only used for A54SX72A with A, B, C, and D corresponding to bottom-left, bottom-right, top-left, and top-right quadrants, respectively. They are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. Each of these clock inputs can drive up to a quarter of the chip, or they can be grouped together to drive multiple quadrants. The clock input is buffered prior to clocking the R-cells. When not used, these pins must be tied Low or High on the board (NOT left floating).

These pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only.

GND **Ground**

Low supply voltage.

HCLK **Dedicated (Hardwired) Array Clock**

This pin is the clock input for sequential modules. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. When not used, HCLK must be tied Low or High on the board (NOT left floating). When used, this pin should be held Low or High during power-up to avoid unwanted static power consumption.

I/O **Input/Output**

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI or 5 V PCI specifications. Unused I/O pins are automatically tristated by the Designer software.

NC **No Connection**

This pin is not connected to circuitry within the device and can be driven to any voltage or be left floating with no effect on the operation of the device.

PRA/B, I/O **Probe A/B**

The Probe pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK, I/O **Test Clock**

Test clock input for diagnostic probe and device programming. In Flexible mode, TCK becomes active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI, I/O **Test Data Input**

Serial input for boundary scan testing and diagnostic probe. In Flexible mode, TDI is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO, I/O **Test Data Output**

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state. When Silicon Explorer II is being used, TDO will act as an output when the checksum command is run. It will return to user I/O when checksum is complete.

TMS **Test Mode Select**

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO, TRST). In flexible mode when the TMS pin is set Low, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-6 on page 1-9). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the logic reset state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The logic reset state is reached five TCK cycles after the TMS pin is set High. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

TRST, I/O **Boundary Scan Reset Pin**

Once it is configured as the JTAG Reset pin, the TRST pin functions as an active low input to asynchronously initialize or reset the boundary scan circuit. The TRST pin is equipped with an internal pull-up resistor. This pin functions as an I/O when the **Reserve JTAG Reset Pin** is not selected in Designer.

V_{CC} **Supply Voltage**

Supply voltage for I/Os. See Table 2-2 on page 2-1. All V_{CC} power pins in the device should be connected.

V_{CCA} **Supply Voltage**

Supply voltage for array. See Table 2-2 on page 2-1. All V_{CCA} power pins in the device should be connected.

Table 2-8 • AC Specifications (5 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4$ ¹	–44	–	mA
		$1.4 \leq V_{OUT} < 2.4$ ^{1, 2}	$(-44 + (V_{OUT} - 1.4)/0.024)$	–	mA
		$3.1 < V_{OUT} < V_{CCI}$ ^{1, 3}	–	EQ 2-1 on page 2-5	–
	(Test Point)	$V_{OUT} = 3.1$ ³	–	–142	mA
$I_{OL(AC)}$	Switching Current Low	$V_{OUT} \geq 2.2$ ¹	95	–	mA
		$2.2 > V_{OUT} > 0.55$ ¹	$(V_{OUT}/0.023)$	–	mA
		$0.71 > V_{OUT} > 0$ ^{1, 3}	–	EQ 2-2 on page 2-5	–
	(Test Point)	$V_{OUT} = 0.71$ ³	–	206	mA
I_{CL}	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load ⁴	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load ⁴	1	5	V/ns

Notes:

1. Refer to the V/I curves in Figure 2-1 on page 2-5. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.
3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 2-1 on page 2-5. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.

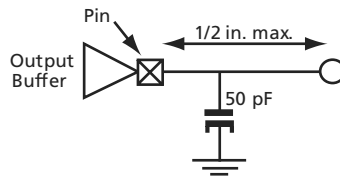


Table 2-17 • **A54SX08A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks										
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.3		1.5		2.3	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.2		1.4		2.0	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.4		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.3		1.5		2.1	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.9	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		1.0		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.7	ns

Table 2-18 • A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.3\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{1,2}										
t _{DLH}	Data-to-Pad Low to High	3.9		4.4		5.2		7.2		ns
t _{DHL}	Data-to-Pad High to Low	3.0		3.4		3.9		5.5		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	13.3		15.1		17.7		24.8		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.8		3.2		3.7		5.2		ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew	13.7		15.5		18.2		25.5		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.9		4.4		5.2		7.2		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.5		2.8		3.3		4.7		ns
t _{ENHZ}	Enable-to-Pad, H to Z	3.0		3.4		3.9		5.5		ns
d _{TLH} ³	Delta Low to High	0.037		0.043		0.051		0.071		ns/pF
d _{THL} ³	Delta High to Low	0.017		0.023		0.023		0.037		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.06		0.071		0.086		0.117		ns/pF

Note:

- Delays based on 35 pF loading.
- The equivalent I/O Attribute Editor settings for 2.5 V LVCMOS is 2.5 V LVTTTL in the software.
- To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HLS]})$$
where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-21 • A54SX16A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.7		0.8		0.9		1.1		1.5	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.5		0.5		0.6		0.7		0.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.7		0.8		0.9		1.1		1.5	ns
Input Module Predicted Routing Delays²												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		0.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2.0		2.2		2.6		3.6	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-28 • A54SX32A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.9		1.1		1.2		1.4		1.9	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		1.4		1.6		1.8		2.1		2.9	ns
Input Module Predicted Routing Delays³												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-35 • A54SX72A Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ²												
t _{PD}	Internal Array Module	1.0		1.1		1.3		1.5		2.0		ns
Predicted Routing Delays ³												
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.3		0.3		0.4		0.6		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.3		0.4		0.5		0.7		ns
t _{RD2}	FO = 2 Routing Delay	0.4		0.5		0.6		0.7		1		ns
t _{RD3}	FO = 3 Routing Delay	0.5		0.7		0.8		0.9		1.3		ns
t _{RD4}	FO = 4 Routing Delay	0.7		0.9		1		1.1		1.5		ns
t _{RD8}	FO = 8 Routing Delay	1.2		1.5		1.7		2.1		2.9		ns
t _{RD12}	FO = 12 Routing Delay	1.7		2.2		2.5		3		4.2		ns
R-Cell Timing												
t _{RCO}	Sequential Clock-to-Q	0.7		0.8		0.9		1.1		1.5		ns
t _{CLR}	Asynchronous Clear-to-Q	0.6		0.7		0.7		0.9		1.2		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.8		1.0		1.4		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.3		1.5		1.7		2.0		2.8		ns
t _{RECASYN}	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Hold Time	0.3		0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Minimum Pulse Width	1.5		1.7		2.0		2.3		3.2		ns
Input Module Propagation Delays												
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS	0.6		0.7		0.8		0.9		1.3		ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS	0.8		1.0		1.1		1.3		1.7		ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI	0.6		0.7		0.7		0.9		1.2		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.7		0.8		0.9		1.0		1.4		ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTTL	0.7		0.7		0.8		1.0		1.4		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTTL	1.0		1.2		1.3		1.5		2.1		ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-36 • **A54SX72A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t _{HPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{HPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{HCKSW}	Maximum Skew		1.4		1.6		1.8		2.1		3.3	ns
t _{HP}	Minimum Period	3.0		3.4		4.0		4.6		6.4		ns
f _{HMAX}	Maximum Frequency		333		294		250		217		156	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.3		2.6		2.9		3.4		4.8	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.8		3.2		3.7		4.3		6.0	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.8		3.2		3.7		5.2	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.9		3.3		3.8		4.5		6.2	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.6		3.0		3.4		4.0		5.6	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		3.1		3.6		4.0		4.7		6.6	ns
t _{RPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{RPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.9		2.2		2.5		3.0		4.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.8		2.1		2.4		2.8		3.9	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.8		2.1		2.4		2.8		3.9	ns
Quadrant Array Clock Networks												
t _{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.6		3.0		3.4		4.0		5.6	ns
t _{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.6		3.0		3.3		3.9		5.5	ns
t _{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.8		3.2		3.6		4.3		6.0	ns
t _{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.8		3.2		3.6		4.2		5.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-36 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.9		3.4		3.8		4.5		6.3	ns
t_{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-38 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.4	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.5	ns
t_{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-39 • A54SX72A Timing Characteristics
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.3\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{2, 3}												
t _{DLH}	Data-to-Pad Low to High	3.9		4.5		5.1		6.0		8.4		ns
t _{DHL}	Data-to-Pad High to Low	3.1		3.6		4.1		4.8		6.7		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	12.7		14.6		16.5		19.4		27.2		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.4		2.8		3.2		3.7		5.2		ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew	11.8		13.7		15.5		18.2		25.5		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.9		4.5		5.1		6.0		8.4		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.1		2.5		2.8		3.3		4.7		ns
t _{ENHZ}	Enable-to-Pad, H to Z	3.1		3.6		4.1		4.8		6.7		ns
d _{TLH} ⁴	Delta Low to High	0.031		0.037		0.043		0.051		0.071		ns/pF
d _{THL} ⁴	Delta High to Low	0.017		0.017		0.023		0.023		0.037		ns/pF
d _{THLS} ⁴	Delta High to Low—low slew	0.057		0.06		0.071		0.086		0.117		ns/pF

Note:

1. All –3 speed grades have been discontinued.
2. Delays based on 35 pF loading.
3. The equivalent IO Attribute settings for 2.5 V LVC MOS is 2.5 V LV TTL in the software.
4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Package Pin Assignments

208-Pin PQFP

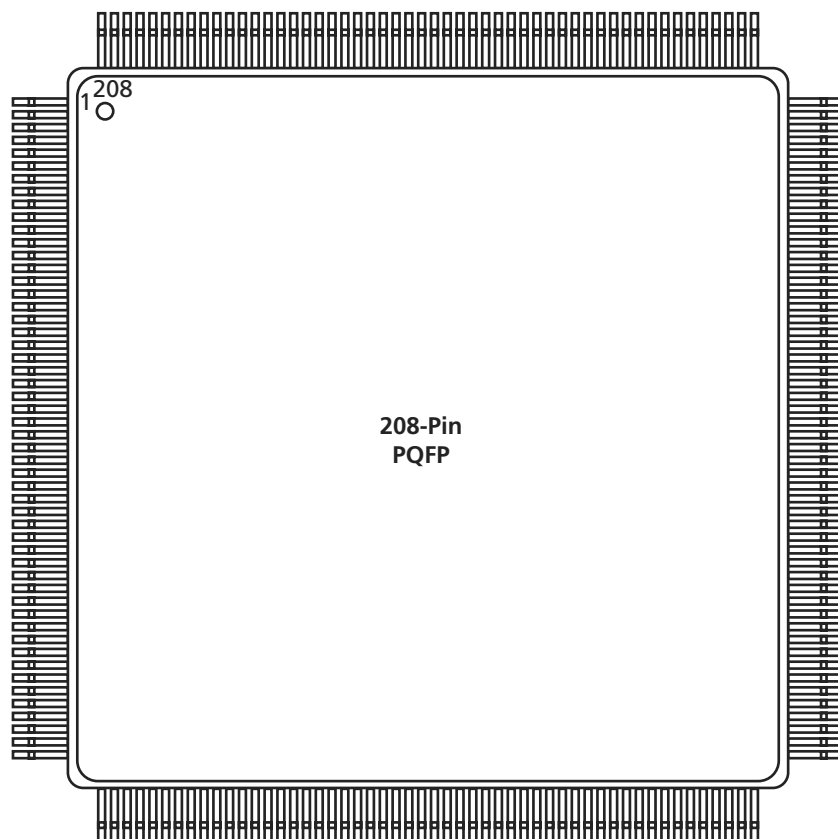


Figure 3-1 • 208-Pin PQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
141	NC	I/O	I/O	I/O
142	I/O	I/O	I/O	I/O
143	NC	I/O	I/O	I/O
144	I/O	I/O	I/O	I/O
145	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
146	GND	GND	GND	GND
147	I/O	I/O	I/O	I/O
148	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
149	I/O	I/O	I/O	I/O
150	I/O	I/O	I/O	I/O
151	I/O	I/O	I/O	I/O
152	I/O	I/O	I/O	I/O
153	I/O	I/O	I/O	I/O
154	I/O	I/O	I/O	I/O
155	NC	I/O	I/O	I/O
156	NC	I/O	I/O	I/O
157	GND	GND	GND	GND
158	I/O	I/O	I/O	I/O
159	I/O	I/O	I/O	I/O
160	I/O	I/O	I/O	I/O
161	I/O	I/O	I/O	I/O
162	I/O	I/O	I/O	I/O
163	I/O	I/O	I/O	I/O
164	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
165	I/O	I/O	I/O	I/O
166	I/O	I/O	I/O	I/O
167	NC	I/O	I/O	I/O
168	I/O	I/O	I/O	I/O
169	I/O	I/O	I/O	I/O
170	NC	I/O	I/O	I/O
171	I/O	I/O	I/O	I/O
172	I/O	I/O	I/O	I/O
173	NC	I/O	I/O	I/O
174	I/O	I/O	I/O	I/O
175	I/O	I/O	I/O	I/O

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
176	NC	I/O	I/O	I/O
177	I/O	I/O	I/O	I/O
178	I/O	I/O	I/O	QCLKD
179	I/O	I/O	I/O	I/O
180	CLKA	CLKA	CLKA	CLKA
181	CLKB	CLKB	CLKB	CLKB
182	NC	NC	NC	NC
183	GND	GND	GND	GND
184	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
185	GND	GND	GND	GND
186	PRA, I/O	PRA, I/O	PRA, I/O	PRA, I/O
187	I/O	I/O	I/O	V _{CCI}
188	I/O	I/O	I/O	I/O
189	NC	I/O	I/O	I/O
190	I/O	I/O	I/O	QCLKC
191	I/O	I/O	I/O	I/O
192	NC	I/O	I/O	I/O
193	I/O	I/O	I/O	I/O
194	I/O	I/O	I/O	I/O
195	NC	I/O	I/O	I/O
196	I/O	I/O	I/O	I/O
197	I/O	I/O	I/O	I/O
198	NC	I/O	I/O	I/O
199	I/O	I/O	I/O	I/O
200	I/O	I/O	I/O	I/O
201	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
202	NC	I/O	I/O	I/O
203	NC	I/O	I/O	I/O
204	I/O	I/O	I/O	I/O
205	NC	I/O	I/O	I/O
206	I/O	I/O	I/O	I/O
207	I/O	I/O	I/O	I/O
208	TCK, I/O	TCK, I/O	TCK, I/O	TCK, I/O

144-Pin TQFP

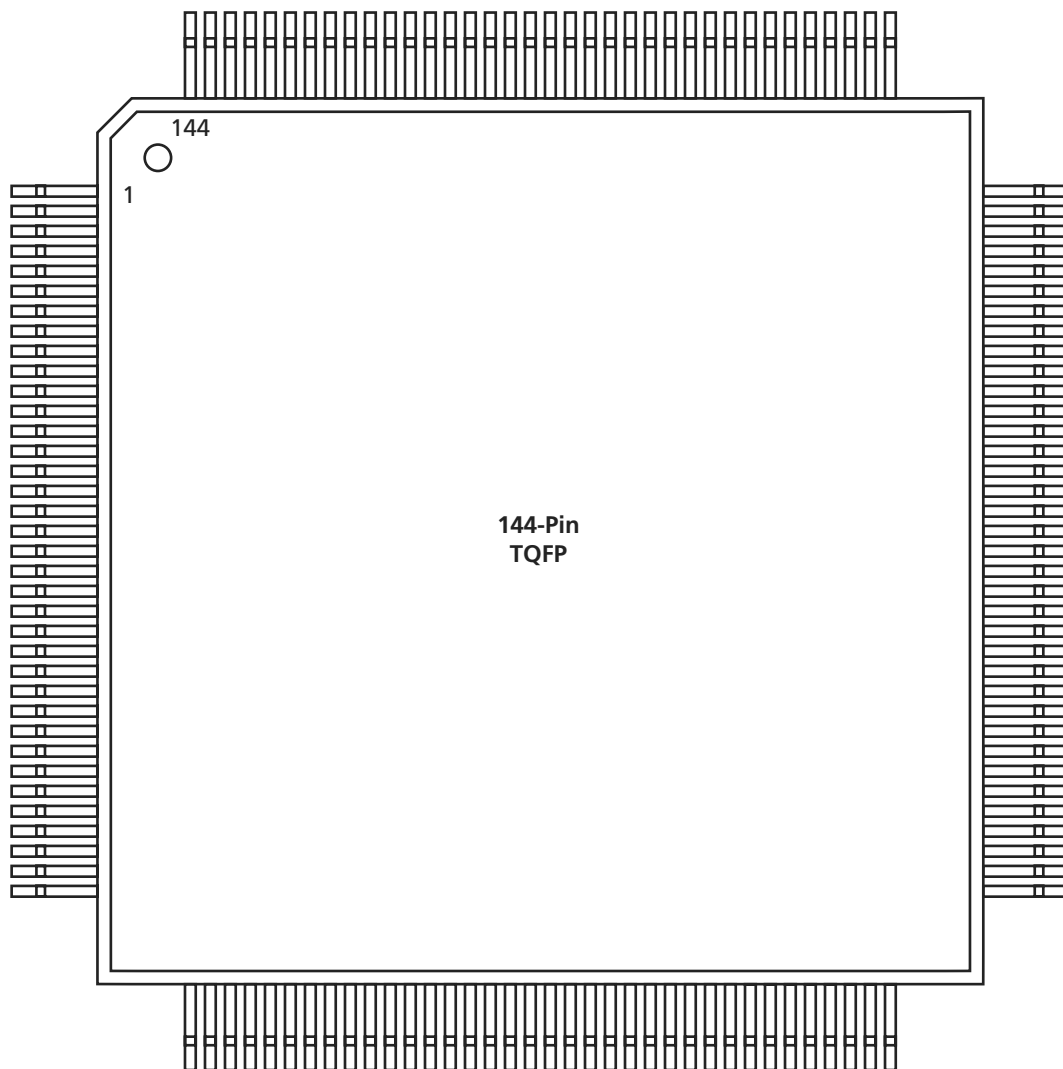


Figure 3-3 • 144-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V _{CCI}	V _{CCI}	V _{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	NC	NC	NC
20	V _{CCA}	V _{CCA}	V _{CCA}
21	I/O	I/O	I/O
22	TRST, I/O	TRST, I/O	TRST, I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V _{CCI}	V _{CCI}	V _{CCI}
30	V _{CCA}	V _{CCA}	V _{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND
37	I/O	I/O	I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V _{CCA}	V _{CCA}	V _{CCA}
57	GND	GND	GND
58	NC	NC	NC
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V _{CCI}	V _{CCI}	V _{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O
73	GND	GND	GND
74	I/O	I/O	I/O

329-Pin PBGA	
Pin Number	A545X32A Function
V22	I/O
V23	I/O
W1	I/O
W2	I/O
W3	I/O
W4	I/O
W20	I/O
W21	I/O
W22	I/O
W23	NC
Y1	NC
Y2	I/O
Y3	I/O
Y4	GND
Y5	I/O
Y6	I/O
Y7	I/O
Y8	I/O
Y9	I/O
Y10	I/O
Y11	I/O
Y12	V _{CCA}
Y13	NC
Y14	I/O
Y15	I/O
Y16	I/O
Y17	I/O
Y18	I/O
Y19	I/O
Y20	GND
Y21	I/O
Y22	I/O
Y23	I/O

256-Pin FBGA			
Pin Number	A545X16A Function	A545X32A Function	A545X72A Function
E11	I/O	I/O	I/O
E12	I/O	I/O	I/O
E13	NC	I/O	I/O
E14	I/O	I/O	I/O
E15	I/O	I/O	I/O
E16	I/O	I/O	I/O
F1	I/O	I/O	I/O
F2	I/O	I/O	I/O
F3	I/O	I/O	I/O
F4	TMS	TMS	TMS
F5	I/O	I/O	I/O
F6	I/O	I/O	I/O
F7	V _{CCI}	V _{CCI}	V _{CCI}
F8	V _{CCI}	V _{CCI}	V _{CCI}
F9	V _{CCI}	V _{CCI}	V _{CCI}
F10	V _{CCI}	V _{CCI}	V _{CCI}
F11	I/O	I/O	I/O
F12	V _{CCA}	V _{CCA}	V _{CCA}
F13	I/O	I/O	I/O
F14	I/O	I/O	I/O
F15	I/O	I/O	I/O
F16	I/O	I/O	I/O
G1	NC	I/O	I/O
G2	I/O	I/O	I/O
G3	NC	I/O	I/O
G4	I/O	I/O	I/O
G5	I/O	I/O	I/O
G6	V _{CCI}	V _{CCI}	V _{CCI}
G7	GND	GND	GND
G8	GND	GND	GND
G9	GND	GND	GND
G10	GND	GND	GND
G11	V _{CCI}	V _{CCI}	V _{CCI}
G12	I/O	I/O	I/O
G13	GND	GND	GND
G14	NC	I/O	I/O
G15	V _{CCA}	V _{CCA}	V _{CCA}

256-Pin FBGA			
Pin Number	A545X16A Function	A545X32A Function	A545X72A Function
G16	I/O	I/O	I/O
H1	I/O	I/O	I/O
H2	I/O	I/O	I/O
H3	V _{CCA}	V _{CCA}	V _{CCA}
H4	TRST, I/O	TRST, I/O	TRST, I/O
H5	I/O	I/O	I/O
H6	V _{CCI}	V _{CCI}	V _{CCI}
H7	GND	GND	GND
H8	GND	GND	GND
H9	GND	GND	GND
H10	GND	GND	GND
H11	V _{CCI}	V _{CCI}	V _{CCI}
H12	I/O	I/O	I/O
H13	I/O	I/O	I/O
H14	I/O	I/O	I/O
H15	I/O	I/O	I/O
H16	NC	I/O	I/O
J1	NC	I/O	I/O
J2	NC	I/O	I/O
J3	NC	I/O	I/O
J4	I/O	I/O	I/O
J5	I/O	I/O	I/O
J6	V _{CCI}	V _{CCI}	V _{CCI}
J7	GND	GND	GND
J8	GND	GND	GND
J9	GND	GND	GND
J10	GND	GND	GND
J11	V _{CCI}	V _{CCI}	V _{CCI}
J12	I/O	I/O	I/O
J13	I/O	I/O	I/O
J14	I/O	I/O	I/O
J15	I/O	I/O	I/O
J16	I/O	I/O	I/O
K1	I/O	I/O	I/O
K2	I/O	I/O	I/O
K3	NC	I/O	I/O
K4	V _{CCA}	V _{CCA}	V _{CCA}

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
C19	I/O	I/O
C20	V _{CCI}	V _{CCI}
C21	I/O	I/O
C22	I/O	I/O
C23	I/O	I/O
C24	I/O	I/O
C25	NC*	I/O
C26	NC*	I/O
D1	NC*	I/O
D2	TMS	TMS
D3	I/O	I/O
D4	V _{CCI}	V _{CCI}
D5	NC*	I/O
D6	TCK, I/O	TCK, I/O
D7	I/O	I/O
D8	I/O	I/O
D9	I/O	I/O
D10	I/O	I/O
D11	I/O	I/O
D12	I/O	QCLKC
D13	I/O	I/O
D14	I/O	I/O
D15	I/O	I/O
D16	I/O	I/O
D17	I/O	I/O
D18	I/O	I/O
D19	I/O	I/O
D20	I/O	I/O
D21	V _{CCI}	V _{CCI}
D22	GND	GND
D23	I/O	I/O
D24	I/O	I/O
D25	NC*	I/O
D26	NC*	I/O
E1	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
E2	NC*	I/O
E3	I/O	I/O
E4	I/O	I/O
E5	GND	GND
E6	TDI, IO	TDI, IO
E7	I/O	I/O
E8	I/O	I/O
E9	I/O	I/O
E10	I/O	I/O
E11	I/O	I/O
E12	I/O	I/O
E13	V _{CCA}	V _{CCA}
E14	CLKB	CLKB
E15	I/O	I/O
E16	I/O	I/O
E17	I/O	I/O
E18	I/O	I/O
E19	I/O	I/O
E20	I/O	I/O
E21	I/O	I/O
E22	I/O	I/O
E23	I/O	I/O
E24	I/O	I/O
E25	V _{CCI}	V _{CCI}
E26	GND	GND
F1	V _{CCI}	V _{CCI}
F2	NC*	I/O
F3	NC*	I/O
F4	I/O	I/O
F5	I/O	I/O
F22	I/O	I/O
F23	I/O	I/O
F24	I/O	I/O
F25	I/O	I/O
F26	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
G1	NC*	I/O
G2	NC*	I/O
G3	NC*	I/O
G4	I/O	I/O
G5	I/O	I/O
G22	I/O	I/O
G23	V _{CCA}	V _{CCA}
G24	I/O	I/O
G25	NC*	I/O
G26	NC*	I/O
H1	NC*	I/O
H2	NC*	I/O
H3	I/O	I/O
H4	I/O	I/O
H5	I/O	I/O
H22	I/O	I/O
H23	I/O	I/O
H24	I/O	I/O
H25	NC*	I/O
H26	NC*	I/O
J1	NC*	I/O
J2	NC*	I/O
J3	I/O	I/O
J4	I/O	I/O
J5	I/O	I/O
J22	I/O	I/O
J23	I/O	I/O
J24	I/O	I/O
J25	V _{CCI}	V _{CCI}
J26	NC*	I/O
K1	I/O	I/O
K2	V _{CCI}	V _{CCI}
K3	I/O	I/O
K4	I/O	I/O
K5	V _{CCA}	V _{CCA}

Note: *These pins must be left floating on the A54SX32A device.

Previous Version	Changes in Current Version (v5.3)	Page
v4.0 (continued)	Table 2-12 was updated.	2-11
	The was updated.	2-14
	The "Sample Path Calculations" were updated.	2-14
	Table 2-13 was updated.	2-17
	Table 2-13 was updated.	2-17
	All timing tables were updated.	2-18 to 2-52
v3.0	The "Actel Secure Programming Technology with FuseLock™ Prevents Reverse Engineering and Design Theft" section was updated.	1-i
	The "Ordering Information" section was updated.	1-ii
	The "Temperature Grade Offering" section was updated.	1-iii
	The Figure 1-1 • SX-A Family Interconnect Elements was updated.	1-1
	The "Clock Resources" section was updated.	1-5
	The Table 1-1 • SX-A Clock Resources is new.	1-5
	The "User Security" section is new.	1-7
	The "I/O Modules" section was updated.	1-7
	The Table 1-2 • I/O Features was updated.	1-8
	The Table 1-3 • I/O Characteristics for All I/O Configurations is new.	1-8
	The Table 1-4 • Power-Up Time at which I/Os Become Active is new.	1-8
	The Figure 1-12 • Device Selection Wizard is new.	1-9
	The "Boundary-Scan Pin Configurations and Functions" section is new.	1-9
	The Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved) is new.	1-11
	The "SX-A Probe Circuit Control Pins" section was updated.	1-12
	The "Design Considerations" section was updated.	1-12
	The Figure 1-13 • Probe Setup was updated.	1-12
	The Design Environment was updated.	1-13
	The Figure 1-13 • Design Flow is new.	1-11
	The "Absolute Maximum Ratings*" section was updated.	1-12
	The "Recommended Operating Conditions" section was updated.	1-12
	The "Electrical Specifications" section was updated.	1-12
	The "2.5V LVCMOS2 Electrical Specifications" section was updated.	1-13
	The "SX-A Timing Model" and "Sample Path Calculations" equations were updated.	1-23
	The "Pin Description" section was updated.	1-15
v2.0.1	The "Design Environment" section has been updated.	1-13
	The "I/O Modules" section, and Table 1-2 • I/O Features have been updated.	1-8
	The "SX-A Timing Model" section and the "Timing Characteristics" section have new timing numbers.	1-23